

X-ray Micro-Tomography of Soils

University of Abertay, Dundee

16th-17th September 2009

Andrew Ramsey, Metris X-Tek

Abstract

How does X-ray micro-tomography allow us to see detailed internal structure in such an inhomogeneous material as soil?

How do we get the best results from a lab-based microfocus X-ray CT scanner?

How do we get a better signal to noise ratio?

How do we maintain high resolution and yet have more X-ray flux?

How do we reduce artefacts in the data?

How do we calibrate dimensional and density measurements?

This presentation will address all these questions to help get the most from an X-ray micro-tomography scanner.